

# LOW POWER HIGH FIDELITY I2S INPUT HEADSET IC

Check for Samples: TLV320DAC3202

## **FEATURES**

- Ground Referenced Click-Pop Free Class-G Stereo Headset Driver
- Capable of Driving 1 VRMS at the Headset Driver Output, Per Channel, in Phase
- 100-dB(A) Channel SNR With 6.5-mW of Quiescent Power Dissipation
- Built In Short-Circuit Protection for Preventing Supply Rails Overload
- Supports 8-, 11.025-, 12-, 16-, 24-, 32-, 44.1and 48-kHz Sample Rates
- I<sup>2</sup>C Interface for Digital Control
- Supports 16-, 20-, 24- and 32-Bit Data Width
- Supports Standard I<sup>2</sup>S, PCM, Left and Right Justified Formats
- Supports Data Mixing With Gain Options

- 32-Step Volume Control from 4 to -59 dB
- Clocking: Internal Clock Derived from I<sup>2</sup>S BCLK
- Package: WCSP, 0.5 mm Pitch, 2 mm x 2.5 mm
- Power Supply: Direct Battery and IO Supply

### **APPLICATIONS**

- Smart Phones and Music Phones
- Portable Navigation
- Personal Media Players
- PDAs
- Portable Game Consoles
- HDD and Flash-Based Portable Audio Players

# **DESCRIPTION**

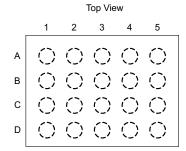
The TLV320DAC3202 is a high fidelity and low power headphone amplifier with integrated DAC and power rails. The small solution size and highly efficient operation maximizes battery life and performance. The digital audio interface supports industry standard formats such as I<sup>2</sup>S and PCM. Many features of this device such as volume setting, data width and sampling rate are configurable for optimum flexibility and efficiency. The headset power control automatically adjusts the rail voltage based on the input signal to maximize efficiency and performance. The control interface uses an industry standard I<sup>2</sup>C controller for ease of operation and reduction in device pin count.

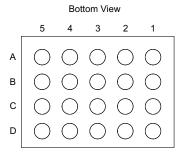
Table 1. ORDERING INFORMATION<sup>(1)</sup>

T <sub>A</sub>		PACKAGE <sup>(2)</sup>	ORDERABLE PART NUMBER
0000 1- 0500		Tape and reel of 250	TLV320DAC3202CYZJT
−30°C to 85°C	Y ZJ	Tape and reel of 3000	TLV320DAC3202CYZJR

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

<sup>(2)</sup> While this part number includes the YZJ package designator, it does not conform to the standard YZJ footprint. Only the drawings below should be used for system design and not the YZJ drawing available from the TI Packaging website.



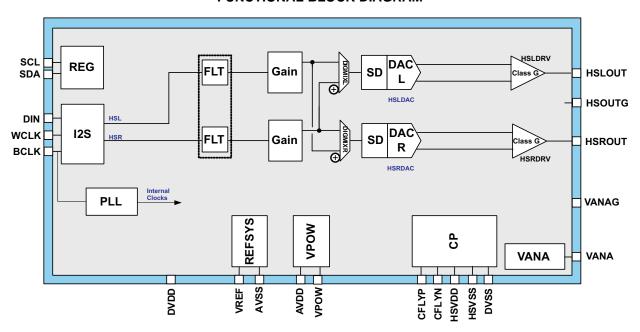




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#### **FUNCTIONAL BLOCK DIAGRAM**



# **PIN ASSIGNMENTS**

# Table 2. PIN ASSIGNMENTS (TOP VIEW)

	1	2	3	4	5
Α	AVSS	VANAG	VANA	CFLYP	CFLYN
В	VREF	AVDD	VPOW	DVDD	DVSS
С	SDA	SCL	HSOUTG	HSVDD	HSOUTL
D	BCLK	WCLK	DIN	HSOUTR	HSVSS

## **Table 3. TERMINAL FUNCTIONS**

TERM	IINAL	1/0	VOLTAGE	DECORIDATION	
NAME	NO.	I/O	LEVEL (V)	DESCRIPTION	
AVSS	A1	Input	0	Analog ground	
VANAG	A2	Input	0	Leave floating	
VANA	А3	Output	1.55	Analog LDO output	
CFLYP	A4	Input/Output	1.95	FLY cap "+" terminal	
CFLYN	A5	Input/Output	-1.95	FLY cap "-" terminal	
VREF	B1	Output	0.75	Analog reference output	
AVDD	B2	Input	VBAT	2.3-V to 4.8-V battery input	
VPOW	В3	Output	1.95	VPOW LDO output	
DVDD	B4	Input	VIO	1.8-V IO digital supply	
DVSS	B5	Input	0	Digital ground	
SDA	C1	Input/Output	VIO	I <sup>2</sup> C Data	
SCL	C2	Input	VIO	I <sup>2</sup> C CLK in	
HSOUTG	C3	Input	0	Headset feedback ground	
HSVDD	C4	Input/Output	1.95	Headset positive supply	
HSOUTL	C5	Output	+/-1.5	Headset output left	
BCLK	D1	Input	VIO	I <sup>2</sup> S bit clock	
WCLK	D2	Input	VIO	I <sup>2</sup> S word clock	
DIN	D3	Input	VIO	I <sup>2</sup> S downlink data	

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#### Table 3. TERMINAL FUNCTIONS (continued)

TERMINAL		1/0	VOLTAGE	DESCRIPTION
NAME	NO.	I/O	LEVEL (V)	DESCRIPTION
HSOUTR	D4	Output	±1.5	Headset output right
HSVSS	D5	Input/Output	-1.95	Headset negative supply

# **ABSOLUTE MAXIMUM RATINGS(1)**

All voltages values are with respect to GND. Over operating free-air temperature range (unless otherwise noted).

			VALUE	UNIT
V/DD (// )	DC	-0.3 to 5	V	
AVDD (V <sub>BAT</sub> )	AC <sup>(2)</sup>		-0.3 to 5.5	V
D\/DD (\/ \)	DC		-0.3 to 2.1	V
DVDD (V <sub>IO</sub> )	AC <sup>(2)</sup>		-0.3 to 2.2	V
T <sub>A</sub>	Operating free air temperature		-40 to 85	°C
$T_{J}$	Maximum junction temperature		125	°C
T <sub>stg</sub>	Storage temperature		-65 to 150	°C
	Lead temperature		115	°C
ECD.	ESD ration (all pine)	Human Body Model	-2000 to 2000	V
	ESD rating (all pins)	Charged Device Model	-500 to 500	V

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

# **RECOMMENDED OPERATING CONDITIONS**

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
T <sub>A</sub>	Operating free air temperature	-30	85	°C
T <sub>stq</sub>	Storage temperature	-55	150	°C

#### **ELECTRICAL CHARACTERISTICS**

AVDD = 3.7 V, DVDD = 1.8 V, T<sub>A</sub> = 25°C, unless otherwise specified.

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
AVDD		Functional only	2.3		4.8	V
(V <sub>BAT</sub> )		Parametric performance	2.3		4.8	V
DVDD (V <sub>IO</sub> )			1.65	1.8	1.95	V
V <sub>IH</sub> , digital <sup>(1)</sup>			0.65 x V <sub>IO</sub>			V
V <sub>IL</sub> , digital <sup>(1)</sup>					0.35 x V <sub>IO</sub>	V
	LICOLITI /D \/altana	Enabled	-1.5		1.5	.,
	HSOUTL/R Voltage	Disabled, HiZ			1.8	V
Power consumption from		No load		6.5		
	all supplies with internal PLL (SNR = 100 dBA)	0.1 mW/channel, 1 kHz, 32 Ω		9.7		mW

(1) CHIP\_EN = 1, HSLEN = 1, HSREN = 1, active I<sup>2</sup>S, idle channel, amplifiers muted

<sup>(2)</sup> For spike duration of 1 ms, 10,000 times over 7 years (lifetime).



# **ELECTRICAL CHARACTERISTICS (continued)**

AVDD = 3.7 V, DVDD = 1.8 V,  $T_A = 25$ °C, unless otherwise specified.

PARAMETER		TEST CONDI	MIN	TYP	MAX	UNIT		
		AVDD, GND mode <sup>(2)</sup>				2		
		DVDD, GND mode <sup>(2)</sup>				2		
	Shutdown current	AVDD, HiZ mode <sup>(3)</sup>				1	μΑ	
		DVDD, HiZ mode <sup>(3)</sup>				1		
	Startup time	From CHIP_EN assertion to Fi state (clock and power supplie			15.5		ms	
	Wake up time	From HSL/R_EN assertion to I state, during which the system powered up with headset drive	is completely		3		ms	
AUDIO PA	ATH ELECTRICAL PERFORM	IANCE						
	Maximum amplitude at ball	0-dB PCM, 1 kHz, THD = 1%, 32-Ω load, 4-dB gain			1.05		Vrms	
		32-Ω load		0.7				
	Amplitude across load	16-Ω load		0.45	0.5		Vrms	
	Dynamic range	1 kHz, -60 dBFs, A-weighted		97	100		dB (A)	
	,		P <sub>OUT</sub> = 20 mW	<u> </u>	68		(-1)	
THD+N		1 kHz, 16-Ω load in series	P <sub>OUT</sub> = 12 mW	70	74		dB	
		with 10 Ω (R <sub>EMI</sub> )	$P_{OUT} = 4 \text{ mW}$		72		l GD	
	Frequency response	20 Hz to 20 kHz	1 001 - 4 11144	-0.25	12	0.25	dB	
	Channel separation	1 kHz, full scale input <sup>(4)</sup>		90	95	0.23	dB	
PSRR	Charmer Separation	217 Hz, 500-mVpp ripple on A	VDD	80	90		dB	
FORK	Pop noise specification (5)			00	90	0.5		
DECEIVE		Maximum DC value after power	· · · · · · · · · · · · · · · · · · ·			0.5	mV	
RECEIVE		PERFORMANCE, F <sub>s</sub> = 44.1 kH	2 OF 40 KHZ		0.0			
	HPF -3 dB corner				8.0		Hz	
	LPF pass band corner frequency	-10 dBF <sub>s</sub>		5		0.42 F <sub>s</sub>	Hz	
	LPF pass band ripple			-0.25		0.25	dB	
	LPF -3 dB corner				0.48 F <sub>s</sub>		Hz	
	LPF interpolation multiplier				8			
	LPF magnitude response	< 0.16 F <sub>s</sub>		-0.05		0.05	dB	
	LPF stop band corner frequency			0.6 F <sub>s</sub>			Hz	
	LPF stop band attenuation	< 2 F <sub>s</sub>		70			dB	
	Absolute delay	Filter only, at 1 kHz, without H Excludes interface + compute		11/ F <sub>s</sub>			s	
AUDIO IN	TERFACE TIMING PARAMET	TERS	1					
T <sub>bclk</sub>	Audio clock period	Variable BCLK			1/BCLK		ns	
T <sub>bclkh</sub>	BCLK high duration			0.35 x BCLK period			ns	
T <sub>bclkl</sub>	BCLK low duration			0.35 x BCLK period			ns	
T <sub>dv</sub>	Data hold time following BCLK falling edge					20	ns	

CHIP\_EN = 0, HIZ\_L = 0, HIZ\_R = 0 CHIP\_EN = 0, HIZ\_L = 1, HIZ\_R = 1

<sup>(4)</sup> The maximum board resistance should be less than 250 mΩ between the HSOUTL/HSOUTR pins and the HSOUTG pin.

<sup>(5)</sup> Maximum slew rate  $(\Delta V/\Delta t) < 5 \text{ V/s after A-weighting}$ 



# **ELECTRICAL CHARACTERISTICS (continued)**

 $\text{AVDD} = 3.7 \text{ V}, \, \text{DVDD} = 1.8 \text{ V}, \, \text{T}_{\text{A}} = 25^{\circ}\text{C}, \, \text{unless otherwise specified}.$ 

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
T <sub>FS</sub>	Sample clock setup time following BCLK falling edge				10	ns
T <sub>ds</sub>	Data set time before BCLK rising edge		0.2 x BCLK period			ns
T <sub>dh</sub>	Data hold time after BCLK rising edge		0.2 x BCLK period			ns
T <sub>wclks</sub>	Short frame sync pulse width			1/BCLK		ns



#### TYPICAL PERFORMANCE CHARACTERISITICS

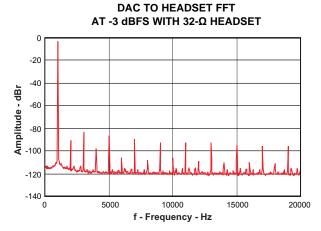
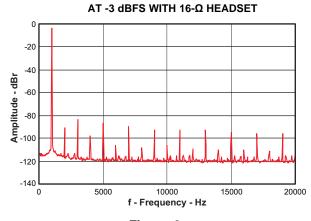


Figure 1.



**DAC TO HEADSET FFT** 

Figure 2.

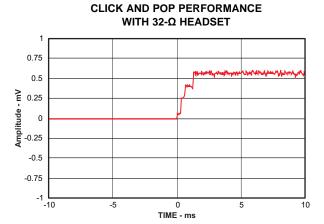


Figure 3.

**TOTAL HARMONIC DISTORTION + NOISE** 

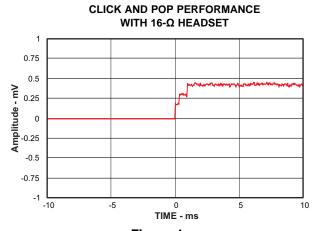
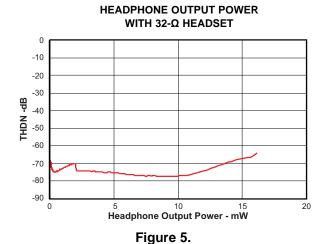


Figure 4.

**TOTAL HARMONIC DISTORTION + NOISE** 

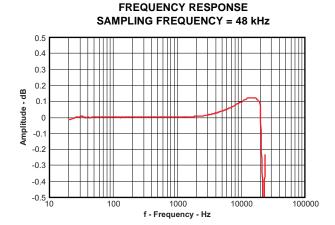
HEADPHONE OUTPUT POWER WITH 16-Ω HEADSET



0 -10 -20 -30 -30 -40 -50 -60 -70 -80 -90 0 5 10 15 20 Headphone Output Power - mW

Figure 6.







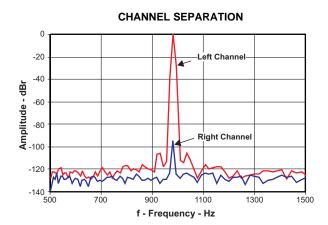


Figure 8.



#### **DIGITAL INTERFACE**

## **Audio Interface**

The audio interface for data communication with application processor or modem supports multiple formats such as I<sup>2</sup>S, left justified, right justified or the short frame sync PCM formats. The default interface format is I<sup>2</sup>S at 48-kHz sampling rate and 16-bit data size. The clock input selection module within PLL block also supports multiple input frequency options. The input clock must be in standard square wave format; hence a clock squarer is not necessary. The following tables shows the details of audio interface configuration through I<sup>2</sup>C register controls.

**Table 4. Audio Interface Format Configuration Register** 

INTF_MODE (1:0)		INTERFACE FORMAT TYPE		
0	0	Standard I <sup>2</sup> S		
0	1	Left justified I <sup>2</sup> S		
1	0	Right justified I <sup>2</sup> S		
1	1	Short PCM		

Table 5. Audio Interface BCLK to WCLK Ratio Setting Register

INTF_FRAME_SIZE (2:0)			INTF_S	SIZE (1:0)	INTERFACE FRAME SIZE, BCLK/WCLK
0	0	0	0	0	2 x 16 x F <sub>s</sub>
0	0	1	0	1	2 x 20 x F <sub>s</sub>
0	1	0	1	0	2 x 24 x F <sub>s</sub>
0	1	1	1	1	2 x 32 x F <sub>s</sub>
1	0	0	0	0	4 x 16 x F <sub>s</sub>
1	0	1	0	1	4 x 20 x F <sub>s</sub>
1	1	0	1	0	4 x 24 x F <sub>s</sub>
1	1	1	1	1	4 x 32 x F <sub>s</sub>

**Table 6. Audio Sampling Rate Setting Register** 

	CLK_M	DDE(3:0)		INTERFACE SAMPLING RATE, WCLK (kHz)
0	0	0	0	8
0	0	0	1	11.025
0	0	1	0	12
0	0	1	1	NA
0	1	0	0	16
0	1	0	1	22.05
0	1	1	0	24
0	1	1	1	NA
1	0	0	0	32
1	0	0	1	44.1
1	0	1	0	48
1	0	1	1	NA
1	1	0	0	NA

Table 7. Detailed Configuration of Interface Including PLL Setup Registers

BCLK/WCLK	DATA SIZE	F <sub>s</sub> (WCLK)	F <sub>s</sub> x DATA	BCLK/PLL INPUT
32	16	48.000	1536	1536
40	20	48.000	1920	1920
48	24	48.000	2304	2304
64	32	48.000	3072	3072

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Table 7. Detailed Configuration of Interface Including PLL Setup Registers (continued)

BCLK/WCLK	DATA SIZE	F <sub>s</sub> (WCLK)	F <sub>s</sub> x DATA	BCLK/PLL INPUT	
32	16	44.100	1411.2	1411.2	
40	20	44.100	1764	1764	
48	24	44.100	2116.8	2116.8	
64	32	44.100	2822.4	2822.4	
64	16	8.000	256	512	
64	16	11.025	352.8	705.6	
64	16	12.000	384	768	
64	16	16.000	512	1024	
64	16	22.050	705.6	1411.2	
64	16	24.000	768	1536	
64	16	32.000	1024	2048	
64	16	44.100	1411.2	2822.4	
64	16	48.000	1536	3072	
80	20	8.000	320	640	
80	20	11.025	441	882	
80	20	12.000	480	960	
80	20	16.000	640	1280	
80	20	22.050	882	1764	
80	20	24.000	960	1920	
80	20	32.000	1280	2560	
80	20	44.100	1764	3528	
80	20	48.000	1920	3840	
96	24	8.000	384	768	
96	24	11.025	529.2	1058.4	
96	24	12.000	576	1152	
96	24	16.000	768	1536	
96	24	22.050	1058.4	2116.8	
96	24	24.000	1152	2304	
96	24	32.000	1536	3072	
96	24	44.100	2116.8	4233.6	
96	24	48.000	2304	4608	
128	32	8.000	512	1024	
128	32	11.025	705.6	1411.2	
128	32	12.000	768	1536	
128	32	16.000	1024	2048	
128	32	22.050	1411.2	2822.4	
128	32	24.000	1536	3072	
128	32	32.000	2048	4096	
128	32	44.100	2822.4	5644.8	
128	32	48.000	3072	6144	



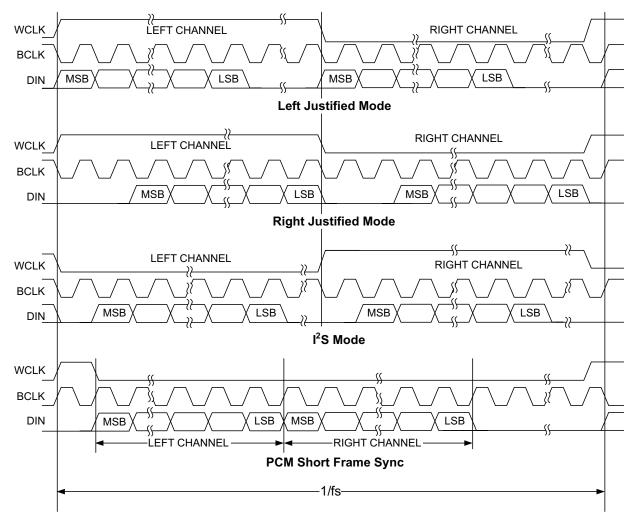


Figure 9. Interface Format Supporting Four Different Options

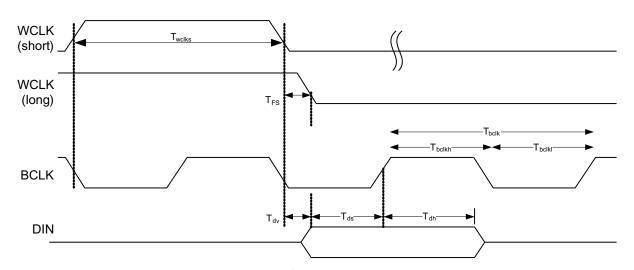


Figure 10. Interface Timing for I<sup>2</sup>S (Long) or PCM (Short) WCLK Options



#### **AUDIO**

### **Channel Performance**

The receive channel of TLV320DAC3202 converts the digital signal to analog for the headset amplifier through a highly efficient low-power DAC. The signal in stereo I<sup>2</sup>S format with configurable data size drives the Class G amplifier after the conversion. The channel gain is implemented in two segments in digital and analog domains. In digital domain the gain steps have finer resolution whereas in the analog domain the amplifier gain steps are defined at 2-dB resolution. The detail of volume control is shown in the register map description. The mixing feature allows the left and right channels to be combined in digital domain prior to conversion and then routed to either channel. The audio signal can be disabled either by soft mute feature in the digital domain or by disabling the output amplifier.

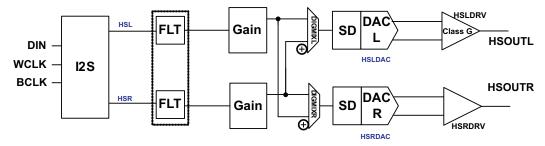


Figure 11. Audio Path Diagram

#### **Volume Control**

The volume control module is implemented with combination of digital and analog gain settings for optimum performance. The total gain range is from 4 dB to -59 dB with variable steps. The gain for the amplifiers is from 4 dB to -12 dB in 2-dB steps.

**Table 8. Volume Control Register Decoding** 

REGISTER VALUE	GAIN (dB)	GAIN_ANALOG (dB)	GAIN_DIGITAL (dB)
31	4	4	0
30	3	4	-1
29	2	2	0
28	1	2	-1
27	0	0	0
26	-1	0	-1
25	-2	-2	0
24	-3	-2	-1
23	-4	-4	0
22	-5	-4	-1
21	-6	-6	0
20	-7	-6	-1
19	-8	-8	0
18	-9	-8	-1
17	-10	-10	0
16	-11	-10	-1
15	-13	-12	-1
14	-15	-12	-3
13	-17	-12	-5
12	-19	-12	-7
11	-21	-12	-9

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Table 8. Volume Control Register Decoding (continued)

REGISTER VALUE	GAIN (dB)	GAIN_ANALOG (dB)	GAIN_DIGITAL (dB)
10	-23	-12	-11
9	-25	-12	-13
8	-27	-12	-15
7	-31	-12	-19
6	-35	-12	-23
5	-39	-12	-27
4	-43	-12	-31
3	-47	-12	-35
2	-51	-12	-39
1	-55	-12	-43
0	-59	-12	-47

#### SYSTEM AND CONTROL

## **Power-Up Sequence**

The power up sequence of the IC is initiated by asserting the CHIP\_EN bit to logic '1'. It is expected that  $V_{BAT}$  and  $V_{IO}$  are powered up prior to assertion of this bit. The HSL/R amplifiers are then enabled by writing to their perspective control bits in register address 0x01. The I<sup>2</sup>S clock must be present prior to power up sequence and maintain its activity during active mode. The figure below shows the typical power up sequence of the IC. The IC power up state machine updates I<sup>2</sup>C register bits corresponding to enabled modules. I<sup>2</sup>C register control can subsequently be used to turn OFF unused circuits.

The power down sequence is initiated by de-asserting the CHIP\_EN bit in CODEC\_EN register. It is expected that the CHIP\_EN bit is de-asserted prior to turning OFF the V<sub>IO</sub> supply.

The HS driver power on/off sequence is designed to be click-pop free.

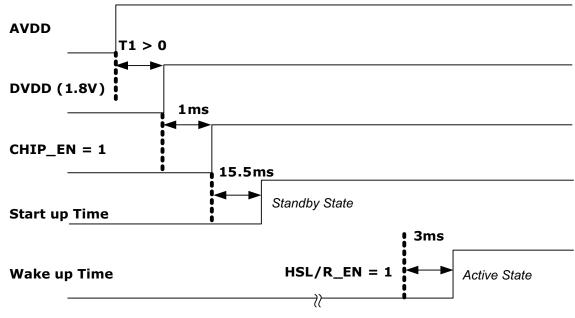


Figure 12. Power-Up Sequence Timing



## **Dual Supply Charge Pump**

The charge pump on TLV320DAC3202 has dual-supply capability module with automatic selection which can be either from  $V_{BAT}$  or  $V_{IO}$  depending on the input signal range and load current that is detected. Charge pump generates both the positive and negative rails for low and high headset rails. For typical listening range where the signal level is low, the supply is expected to be from  $V_{IO}$  and headset rail is 0.9 V. For higher signal levels where higher current drains from  $V_{IO}$  are not possible, the IC uses an automatic input voltage and load current threshold based algorithm to switch ON the  $V_{POW}$  regulator and use  $V_{POW}$ , which is powered from  $V_{BAT}$ . It is designed to power the left and right headset drivers up to rated full scale output.

The threshold point to transition between the low and high power range can be programmed through I<sup>2</sup>C interface. There are two threshold points controlled by register bits, one for each of left and right channels. The threshold monitor mechanisms for each channel can be independently enabled and programmed. The load current threshold settings can be 10.5 mA, 11.5 mA, 12.5 mA (default) or 13.5 mA per channel.

### **Output Impedance**

In order to share the output connector between audio and other signals such as video output, a high impedance option is implemented that can be enabled through I<sup>2</sup>C controller. In this mode the output impedance is increased while the signal is muted. As shown in below table the output impedance is large enough to avoid an unwanted attenuation of other signal connected to the jack contact.

CHIP\_EN HiZ HS\_EN **IMPEDANCE** MODE 0 0 0 150 Ω Shut down 0 0 1 150 Ω Shut down 8.5 Ω at 40 kHz 0 0  $600~\Omega$  at 6~MHzHiZ1 400 Ω at 13 MHz 0 Invalid 1 1 1 0 0 150 Ω Active, HS off 1 1 0 Active 1 1 0 Invalid Invalid 1 1 1

**Table 9. Output Impedance in Various Mode Settings** 

### I<sup>2</sup>C INTERFACE

The control interface for programming the registers on TLV320DAC3202 is done using a standard I<sup>2</sup>C interface with the IC operating in slave mode. The 2 modes of operation as defined in Ref [1,2] are (a) Standard-mode up to 100 kbit/s, and (b) Fast-mode up to 400 kbit/s. The IC defaults to fast-mode. A 7-bit slave addressing is used. The device I<sup>2</sup>C slave address is fixed to 0011010X, with 00110100 for master write cycle (TLV320DAC3202 reads) and 00110101 for master read cycle (TLV320DAC3202 writes). For data and clock lines, pull up resistors are required and are expected to be provided as defined in section 7 of Ref [1].

#### References

[1] UM10204: I<sup>2</sup>C-Bus Specification and user manual Rev. 03 – 19 June 2007

[2] The I<sup>2</sup>C-BUS SPECIFICATION VER 2.1 January 2000

[3] I<sup>2</sup>S Bus specification, Phillips Semiconductors, June 1996



# **Register Map**

# Table 10. Register Map Designation for I<sup>2</sup>C Interface

ADDRESS	REGISTER	D7	D6	D5	D4	D3	D2	D1	D0	INITIAL VALUE	ACCESS (R, W, WR)
0x00											
0x01	EN	HSL_EN	HSR_EN	-	-	-	-	THERMAL	CHIP_EN	0x00	R
0x02	VOL_CTRL	HSL_MUTE	HSR_MUTE			VOLCTRL(4:0)			-	0xC0	WR
0x03	HIZ_CTRL	-	-	SPARE	SPARE	-	-	HIZ_L	HIZ_R	0x00	WR
0x04	ASICREV		ASICI	D(3:0)			VERSI	ON(3:0)		0x00	R
0x05	I2CID				I2CI	D(7:0)				0x34	R
0x06	HS_LP2HP _SW1	HS_LP_MODE	HS_BYPASS _CUR_SW	-	-	HSL_CUR_THRI	D(1:0)	HSR_CUR	_THRD(1:0)	0x00	WR
0x07	CODEC_EN	HSL_DRV_EN	HSR_DRV_EN	CP_EN	PLL_EN	REF_EN	-	DACL_EN	DACR_EN	0x00	W
80x0	CODEC_CTRL	HSL_FIR_EN	HSR_FIR_EN	HSL_RAMP _DIS	HSR_RAMP _DIS	HSL_MIX_	_CTRL(1:0)	HSR_MIX_	_CTRL(1:0)	0x00	WR
0x09	INTF	INTF_M	ODE(1:0)	INTF_DAT	A_SIZE(1:0)	-	INI	F_FRAME_SIZE(	2:0)	0x00	WR
0x0A	FIR		CLK_MC	DDE(3:0)		-	-	INTERPOL	ATION(1:0)	0xA3	WR
0x0B	CP	CP_OPEN	CP_HPMODE	CP_ENCLAMP		CP_FET_SIZE(2:0	)	-	-	0x00	WR
0x0C	REF	-	-	REF_CM_HIG	SH_SWING(1:0)		REF_C	UR(3:0)		0x00	WR
0x0D	DAC	DAC_INV_CLK	OFFSET _CORR_EN	-	-	DACR_SWING	DACL_SWING	DACR_LP	DACL_LP	0x00	WR
0x0E	HS_LP2HP _SW2	HP_LOW _IBIAS	HS_BYPASS _SHTDN	HS_SW_OVE	HS_SW_OVER_SPEED(1:0) HS_AMP_SW_OVER(1:0) HS_HIGHAMP_SW_OVER(1:0)			0x80	WR		
0x11	PM_EN	REFSYS_EN	-	SPARE_W	VANA_EN	-	VPOW_EN	-	-	0x00	W
0x12	PM_LDO	-	-	VPOW_	OUT(1:0)	-	-	VANA_0	OUT(1:0)	0x00	WR
0x18	UNLOCK_PM	-	-	-	-	-	-	-	UNLOCK_PM	0x00	WR
0x19	PM_TEST1	TEST_REFSYS _SET_BG	EEPROM _BYPASS	SPARE	TEST_VANA _HIZ	-	TEST_VPOW _HIZ	EEPROM _PROGRAM	DIEID _PROGRAM	0X00	WR
0x1A	HS_TEST	SPARE	SPARE	TEST_HSL _TM1	TEST_HSL _OCDIS	TEST_DC2DAC	TEST_ISUM _DETECT	TEST_HSR _TM1	TEST_HSR _OCDIS	0x00	WR
0x1B	CODEC_TEST1		CODEC_TES	ST_MUX(3:0) TEST_BYP_FIR TEST_CP_CLK(2:0)				0x00	WR		
0x1C	CODEC_TEST2	TEST_BYP _MOD	TEST_BYP _RANDOMIZER	TEST_PLL_ OVERRIDE_EN  PLL_PRE_DIV_OVR(4:0)				0x00	WR		
0x1D	CODEC_TEST3	SPARE		PLL_FB_LOOP_OVR(6:0)			0x00	WR			
0x1E	CODEC_TEST4	CP_TE	ST(1:0)	PLL_TEST_MODE_L(5:0)			0x30	WR			
0x1F	CODEC_TEST5	PLL_TEST_MODE_H(7:0)				0x00	WR				

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## **PCB DEVELOPMENT**

The following table explains the PCB recommendations. In addition, it is recommended to split the ground plane into analog and digital segment for clean and noisy signals. They should be connected only in a single point to avoid ground loop.

**Table 11. PCB Recommendations** 

BALL NAME	DESCRIPTION	LAYOUT RECOMMENDATIONS
AVSS	Analog ground	
VANAG	Connected to VANA via capacitor	Connect to output capacitor with $< 10 \text{ m}\Omega$ .
VANA	Analog LDO output	Connect to output capacitor with $< 10 \text{ m}\Omega$ .
DVDD	IO/Digital supply	Minimize the resistance path with adequate decoupling very close to the ball.
CFLYP	FLY capacitor "+" terminal	Connect to positive side of output capacitor with $< 10 \text{ m}\Omega$ .
VREF	Analog reference output	Connect to AVSS via output capacitor. The capacitor trace on the AVSS side of the capacitor should not be connected to GND plane directly but at the AVSS pin. See application diagram.
AVDD	2.3-V to 4.8-V battery input	Minimize the resistance path with adequate decoupling very close to the ball.
VPOW	CP LDO output	Minimize the resistance path with adequate decoupling very close to the ball.
DVSS	Digital ground	Connect to separate GND plane for noisy signals, i.e. PLL and interfaces. Connect the two planes in a single point to avoid GND loop.
CFLYN	FLY capacitor "-" terminal	Connect to negative side of output capacitor with $< 10 \text{ m}\Omega$ .
SDA	I <sup>2</sup> C data	Keep this away from clean quite signal paths over the digital GND plane.
SCL	I <sup>2</sup> C CLK in	Keep this away from clean quite signal paths over the digital GND plane.
HSOUTG	HS feedback ground	Trace impedance must be very small, < 60 m $\Omega$ . This is important for cross talk reduction. Connection to GND plane must be at IC ball.
HSVDD	HS positive supply	Decouple this path to DVSS with trace impedance of $< 20 \text{ m}\Omega.$
HSOUTL	HS output left	Must be routed in differential pair with GNDHS to the connector. Match the impedances and as small as possible.
DIN	I <sup>2</sup> S downlink data	Keep this trace away from quite GND/signal traces.
WCLK	I <sup>2</sup> S word clock	Keep this trace away from quite GND/signal traces.
BCLK	I <sup>2</sup> S bit clock	Keep this trace away from quite GND/signal traces.
HROUTR	HS output right	Must be routed in differential pair with GNDHS to the connector. Match the impedances and as small as possible.
HSVSS	HS negative supply	Decouple this path to DVSS with trace impedance of $<20\ m\Omega.$



## TYPICAL CIRCUIT CONFIGURATION

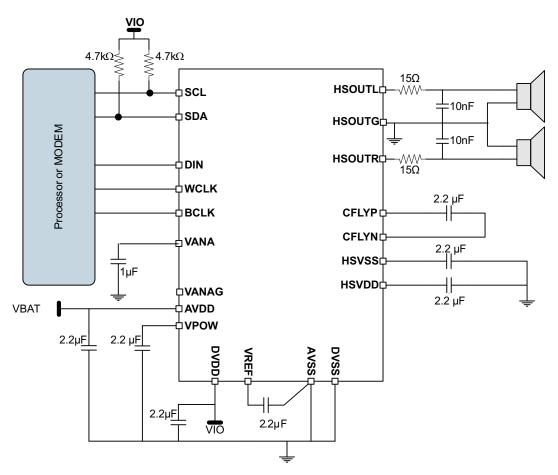


Figure 13. Typical Circuit

Table 12. External Component List(1)

PIN NAME	DESCRIPTION		
AVDD	2.2 μF, 6.3-V tolerance		
VPOW	2.2 μF, 6.3-V tolerance		
VREF	2.2 μF, 6.3-V tolerance		
VANA	1 μF, 6.3-V tolerance		
HSVDD	2.2 μF, 6.3-V tolerance		
HSVSS	2.2 μF, 6.3-V tolerance		
CFLYP/N	2.2 μF, 6.3-V tolerance		
DVDD	2.2 μF, 6.3-V tolerance		

(1) The headset amplifiers output power and distortion are characterized using the nominal capacitance for the supply, ground, output loads, and the charge pump fly cap as shown in the above application diagram. To meet the stated performance with discrete component variations, it is recommended that the external components be chosen to account for manufacturing tolerance, voltage and temperature de-rating.

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